

<p>Search Notes</p> 				<p>Application/Control No.</p> <p>10/656,301</p> <p>Examiner</p> <p>ANH H. DO</p>	<p>Applicant(s)/Patent under Reexamination</p> <p>LEE ET AL.</p> <p>Art Unit</p> <p>2624</p>	
SEARCHED				SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
Class	Subclass	Date	Examiner		DATE	EXMR
386	52, 55	6/20/2007	AD	EAST	6/20/2007	AD
382	232,					
INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner		DATE	EXMR